

HYPOTHESIS TESTING

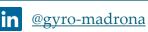
INFERENTIAL STATISTICS

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TOPIC OUTLINE

Hypothesis Test

Significance Level

Rejection Region

Critical Value and Z-score



HYPOTHESIS TEST



HYPOTHESIS

A <u>hypothesis</u> is an initial <u>assumption</u> formed before collecting data, and it serves as a statement about a <u>population</u> parameter rather than about the sample data.

Steps in Data-Driven Decision Making

- 1. Formulate a hypothesis
- 2. Find the right test (e.g., z-test, t-test)
- 3. Execute the test
- 4. Make a decision





HYPOTHESIS TEST

A <u>hypothesis test</u> is simply comparing reality to an assumption and asking, "<u>Did things</u> <u>change?</u>"

Null Hypothesis (H_o)

Represents **no change**, no effect, or the status quo.

Alternative Hypothesis (H_a)

Represents the possibility that things did change or that there is a **significant difference**.

A fitness tracker company claims their device measures heart rate with 95% accuracy compared to medical-grade monitors. An independent lab wants to verify this claim.

Null Hypothesis

$$H_o$$
: $\mu_o = 95$

The average accuracy is 95%.

<u>Alternative Hypothesis</u>

*H*_a:
$$\mu_o \neq 95$$

The average accuracy differs from 95%.



A manufacturer claims that their new energy-efficient LED bulbs have an average lifespan of **at least 25,000 hours**. A consumer group suspects that the actual lifespan is shorter and decides to test this claim.

Null Hypothesis

 H_o : $\mu_o = 25,000$

The average lifespan of the LED is 25,000 hours.

Alternative Hypothesis

 H_a : $\mu_o < 25,000$

The average lifespan of the LED is less than 25,000 hours.

A study suggests that storing apples in a controlled atmosphere **extends** their shelf life beyond **30 days**. A food scientist wants to verify if this method truly increases shelf life compared to conventional storage.

Null Hypothesis

$$H_o$$
: $\mu_o = 30$

Controlled-atmosphere storage shelf life is 30 days.

Alternative Hypothesis

$$H_a$$
: $\mu_o > 30$

Controlled-atmosphere storage increases shelf life beyond 30 days.

SIGNIFICANCE LEVEL



SIGNIFICANCE LEVEL

The <u>significance level</u> (α) determines the threshold for deciding whether to <u>reject</u> the null hypothesis (H_o).

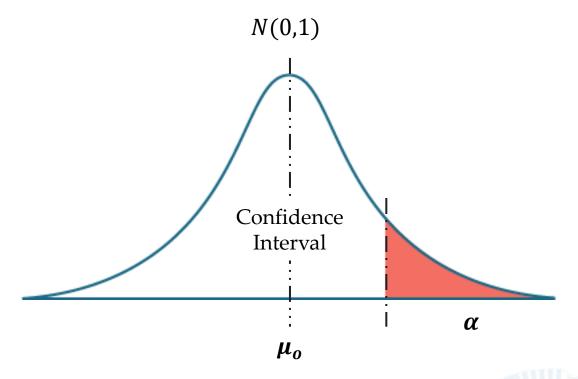
Typical values for α :

0.01

0.05

0.1

Standard Normal Distribution



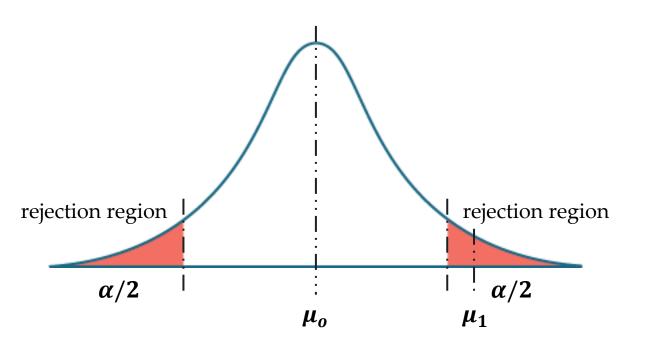
REJECTION REGION

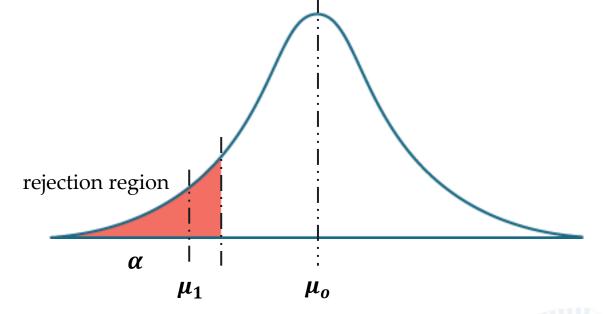


REJECTION REGION

Two-Tailed Test

One-Tailed Test





$$H_o$$
: $\mu_1 = \mu_o$

$$H_a$$
: $\mu_1 \neq \mu_o$

$$H_o$$
: $\mu_1 = \mu_o$

$$H_a$$
: $\mu_1 < \mu_o$



REJECTION REGION

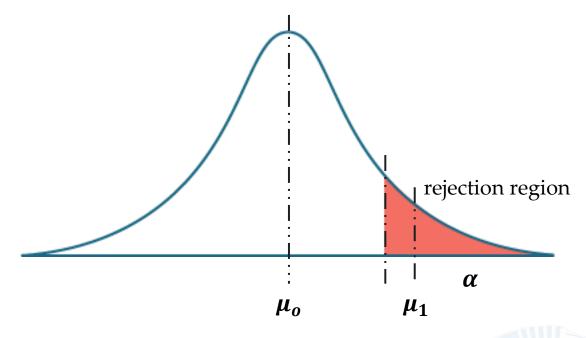
Two-Tailed Test

rejection region $\alpha/2$ μ_1 μ_o rejection region

 H_o : $\mu_1 = \mu_o$

 H_a : $\mu_1 \neq \mu_o$

One-Tailed Test



$$H_o$$
: $\mu_1 = \mu_o$

$$H_a$$
: $\mu_1 > \mu_0$



CRITICAL VALUE AND Z-SCORE



CRITICAL VALUE AND Z-SCORE

lowercase **z**

z refers to the <u>critical value</u> obtained from the standard normal distribution table (ztable).

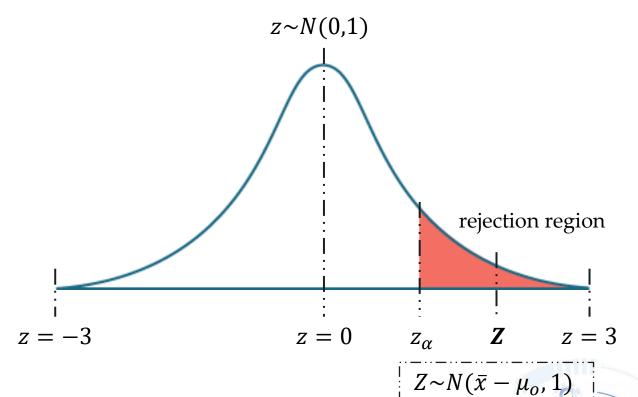
uppercase **Z**

Z is a standardized variable associated with the test called the **Z-score**.

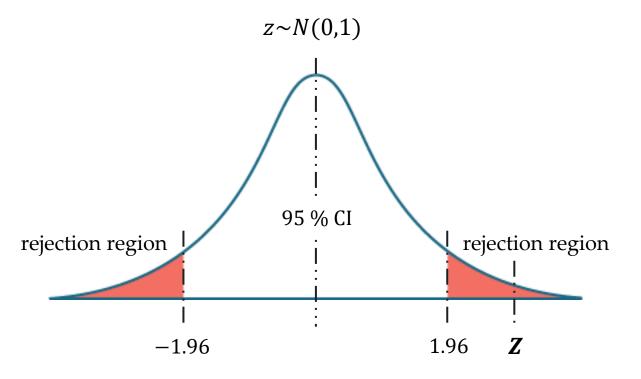
Formula:

$$Z = \frac{\overline{x} - \mu_o}{\sigma / \sqrt{n}}$$

One-Tailed Test



Two-Tailed Test



$$\alpha = 0.05$$

$$z_{0.025} = 1.96$$

Null Hypothesis

$$H_o$$
: $\mu_o = 95$

The average accuracy is 95%.

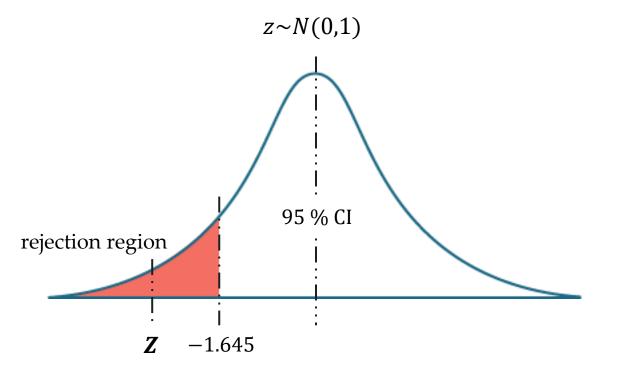
Alternative Hypothesis

$$H_a$$
: $\mu_o \neq 95$

The average accuracy differs from 95%.



One-Tailed Test



$$\alpha = 0.05$$

$$z_{0.05} = 1.645$$

Null Hypothesis

 H_o : $\mu_o = 25,000$

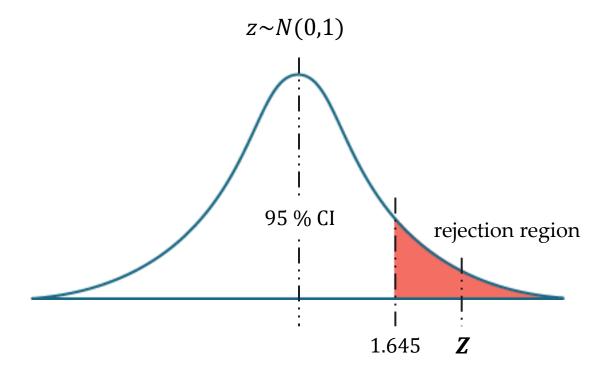
The average lifespan of the LED is 25,000 hours.

Alternative Hypothesis

 H_a : $\mu_o < 25,000$

The average lifespan of the LED is less than 25,000 hours.

One-Tailed Test



$$\alpha = 0.05$$

$$z_{0.05} = 1.645$$

Null Hypothesis

$$H_o$$
: $\mu_o = 30$

Controlled-atmosphere storage shelf life is 30 days.

Alternative Hypothesis

$$H_a$$
: $\mu_o > 30$

Controlled-atmosphere storage increases shelf life beyond 30 days.

A manufacturing process is claimed to have an average defect rate of **10.32** units, with a known standard deviation of **3.17** units. The Statistical Process Control (SPC) department suspects this claim may no longer be valid and collects a **random sample** of **30** production units to test whether the true average **defect rate differs** significantly from **10.32**.

Dataset:

<u>defects-data-30-samples.csv</u>

Solution:



LABORATORY

